

Cryogenic Refractive Index of Heraeus Homosil Glass

Kevin H. Miller

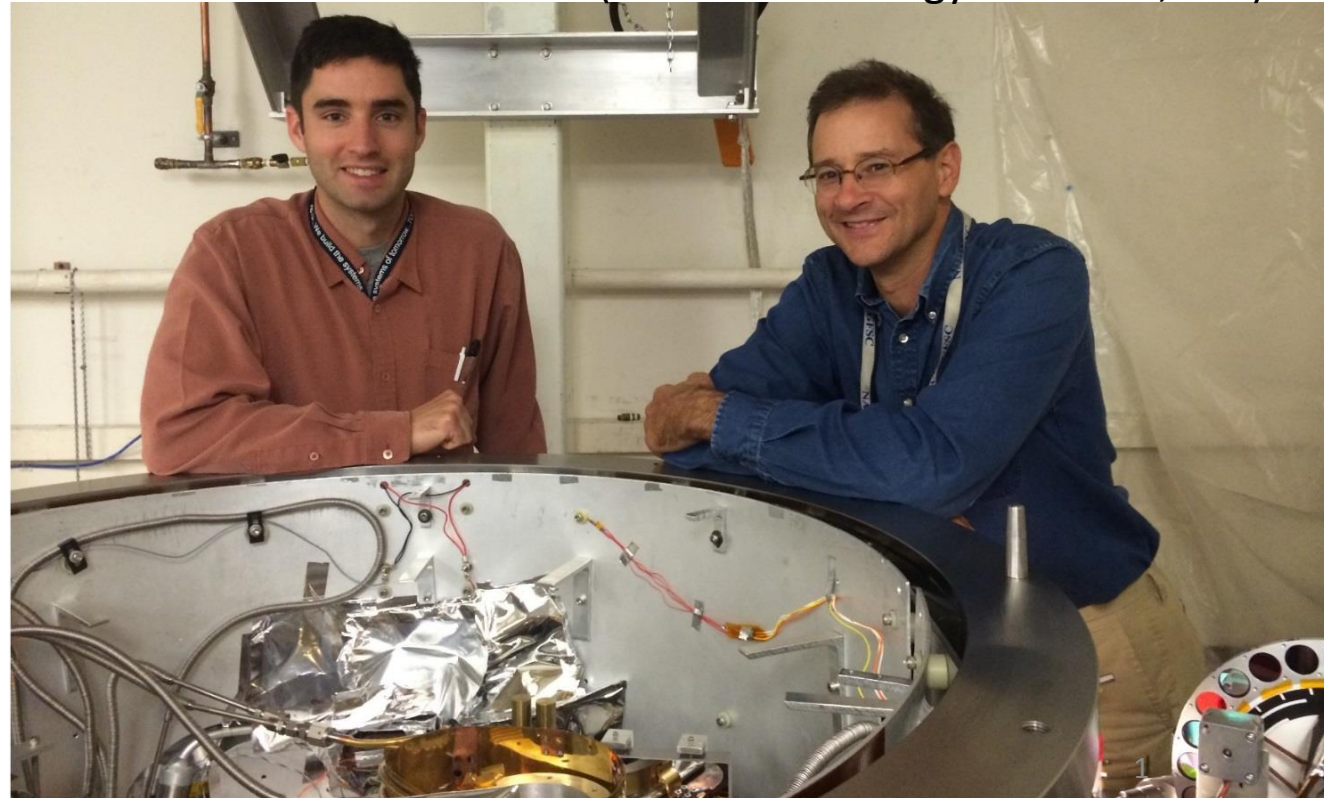
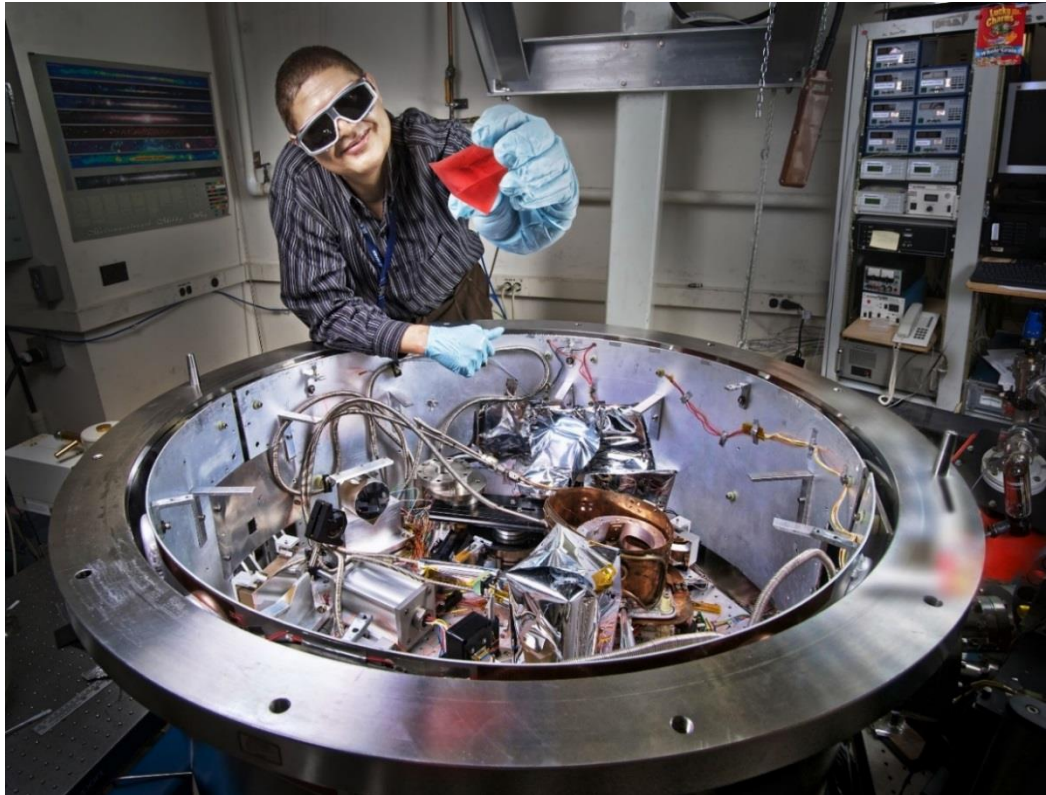
NASA Goddard Space Flight Center, Optics Branch

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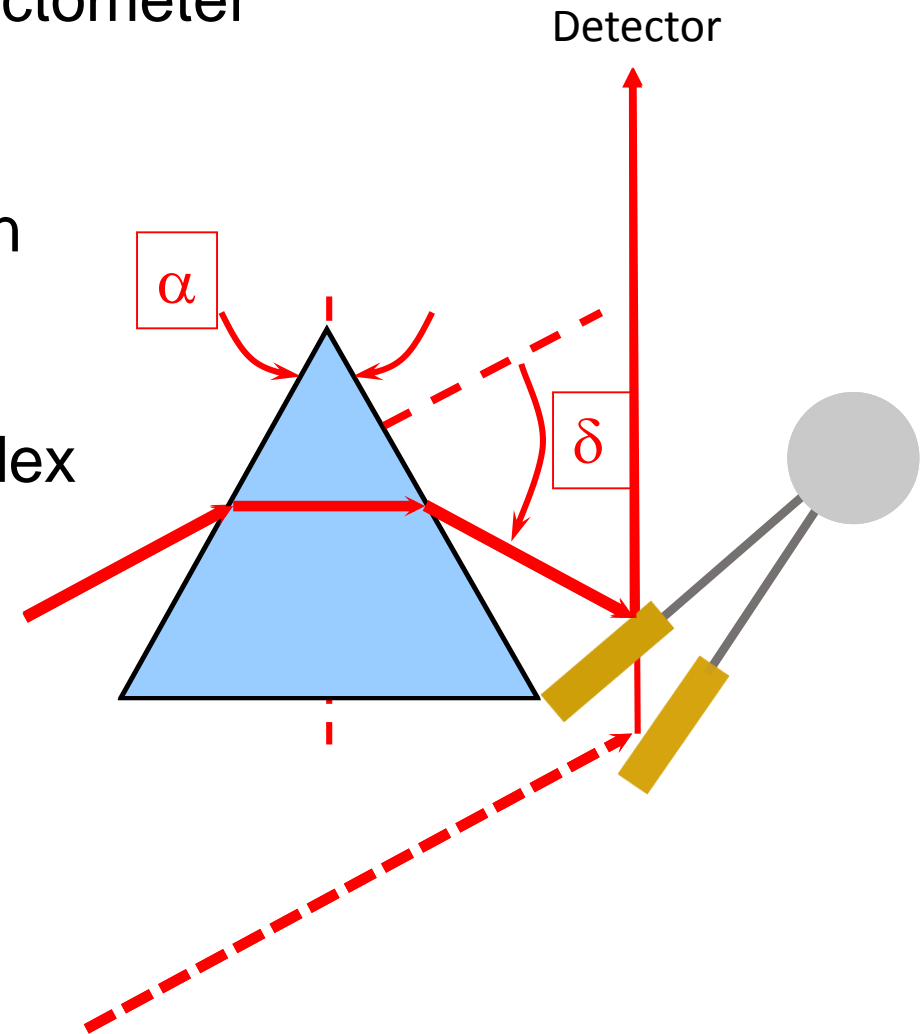
CHARMS Capabilities

- Absolute minimum deviation refractometer (in vacuum)
- Wavelength coverage: 0.34 to 5.6 μm
- Temperature coverage: 15 K (using LHe) to 340⁺ K (67 C)
- Single measurement ABSOLUTE accuracies as good as 5×10^{-6} at cryo (depending on material)
- Measures absolute refractive index, $n(\lambda, T)$
- Accurate values of thermo-optic coefficient, dn/dT , and spectral dispersion, $dn/d\lambda$, derived from measured $n(T)$

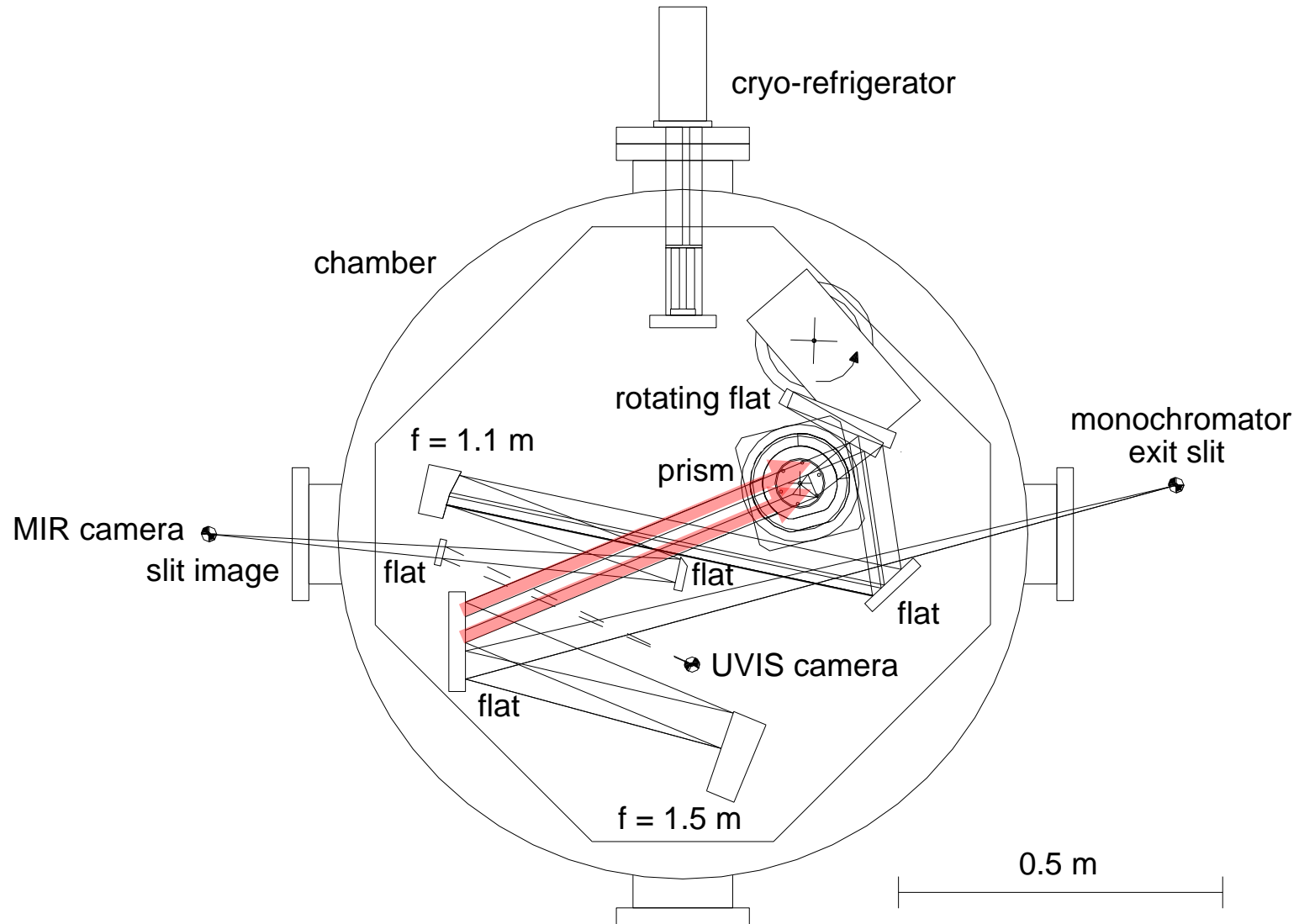
CHARMS: Operation and Capabilities

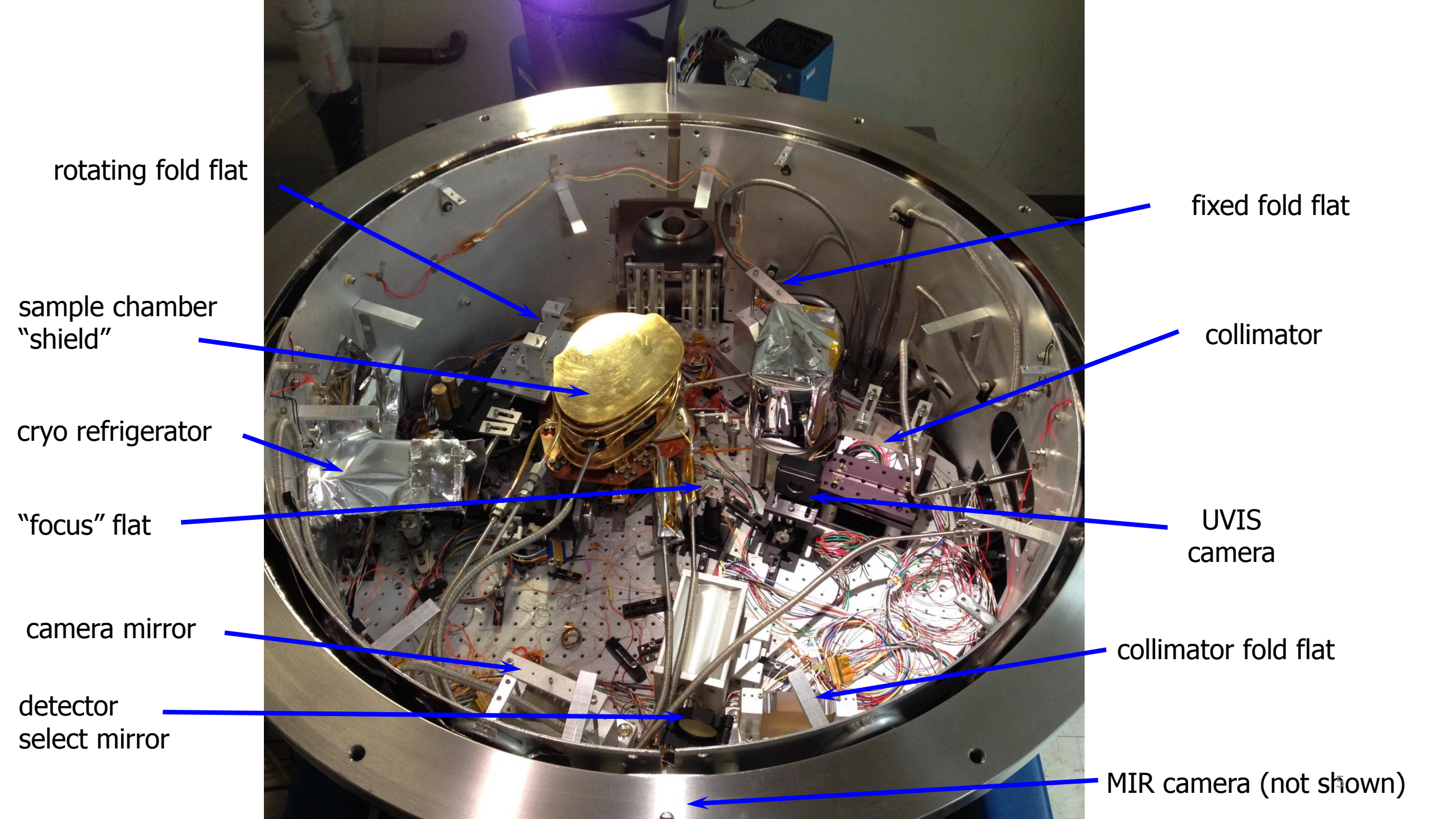
- CHARMS is a minimum deviation refractometer
- Five simple steps:
 1. Measure the apex angle of the prism
 2. Establish the condition of min deviation
 3. Measure angle of undeviated beam
 4. Measure angle of deviated beam
 5. Compute deviation angle; compute index

$$n = \frac{\sin\left(\frac{\alpha + \delta}{2}\right)}{\sin\left(\frac{\alpha}{2}\right)}$$



CHARMS optical layout





rotating fold flat

fixed fold flat

sample chamber
"shield"

collimator

cryo refrigerator

"focus" flat

UVIS
camera

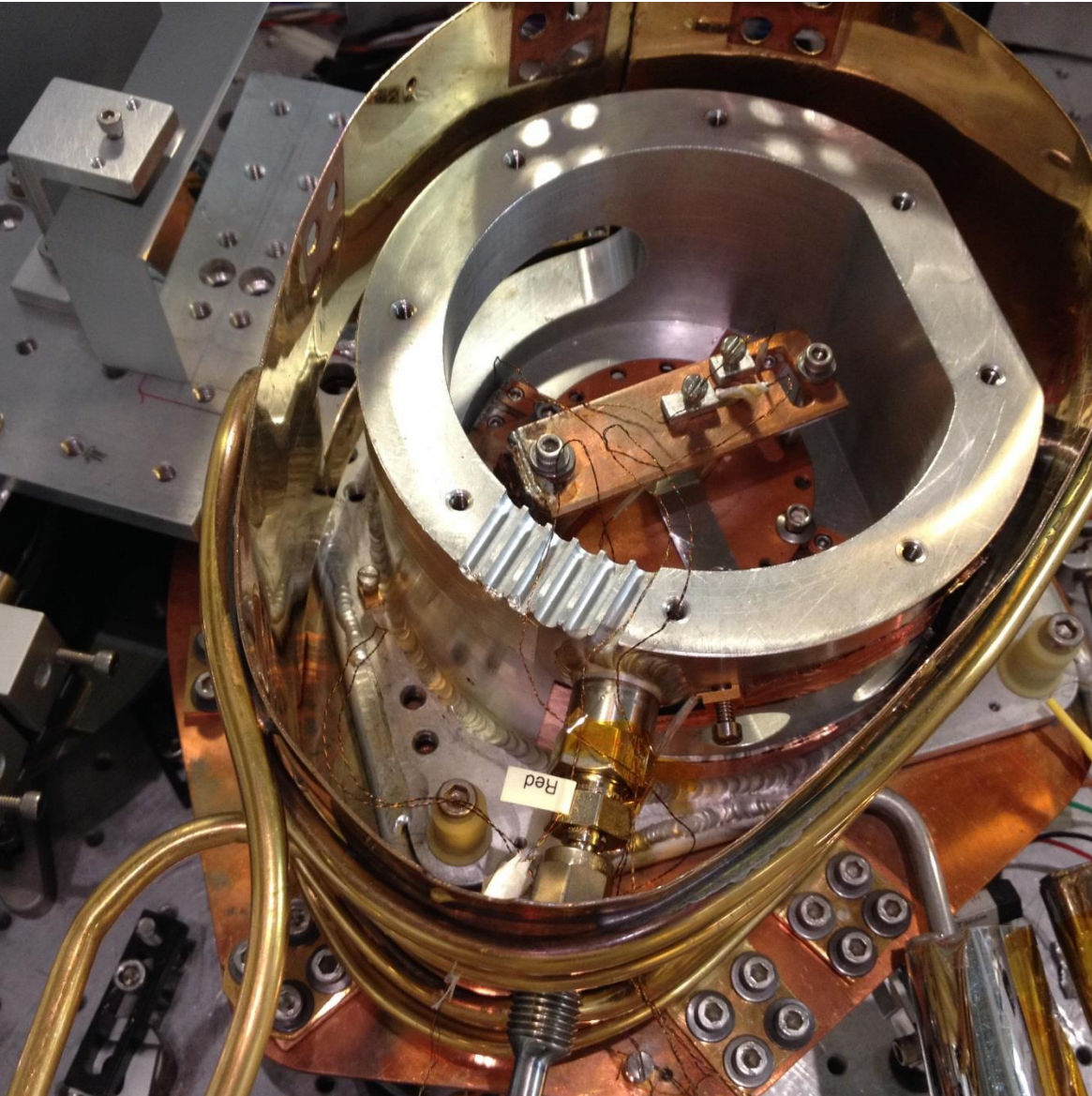
camera mirror

collimator fold flat

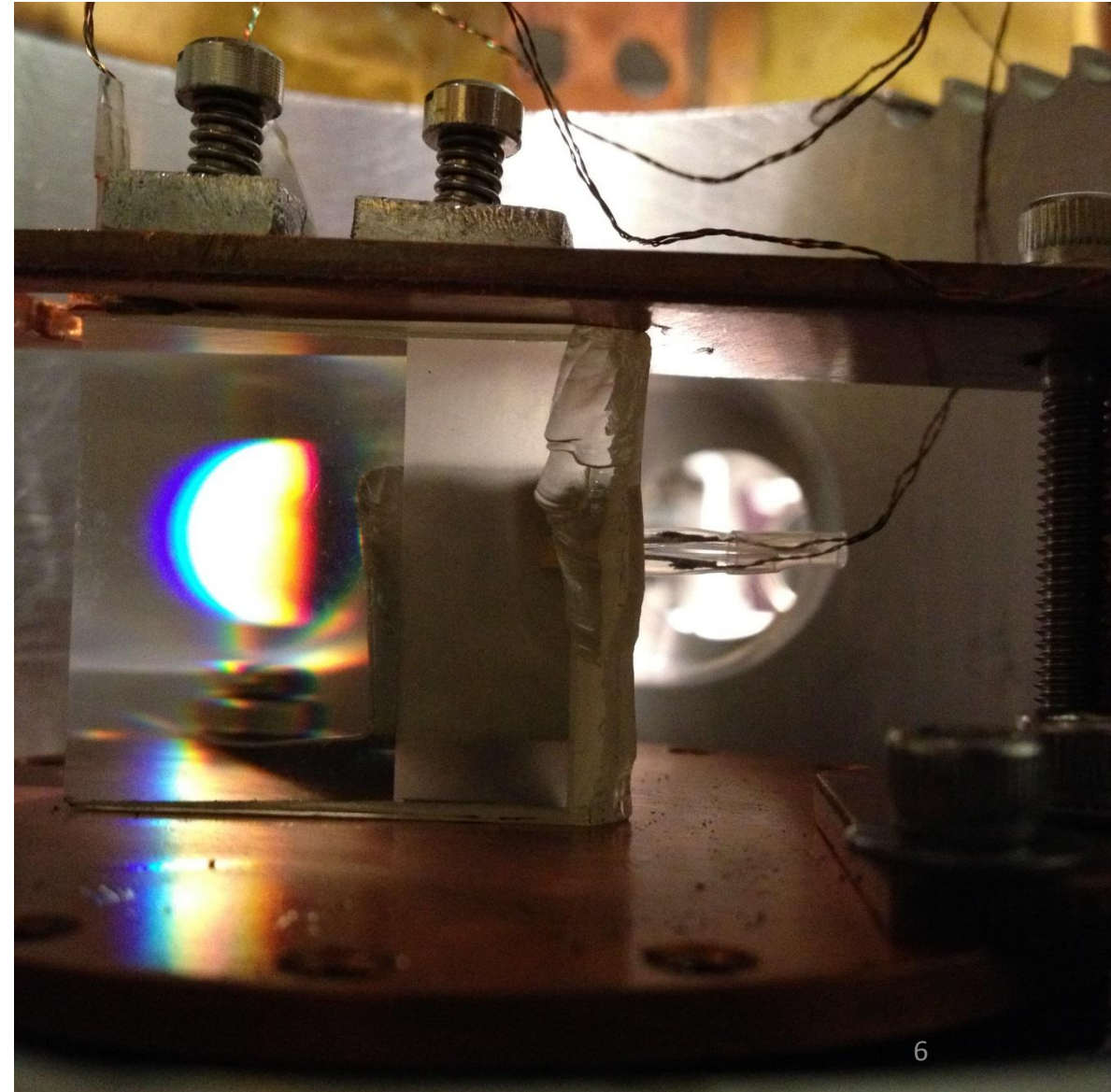
detector
select mirror

MIR camera (not shown)

Top view of sample chamber

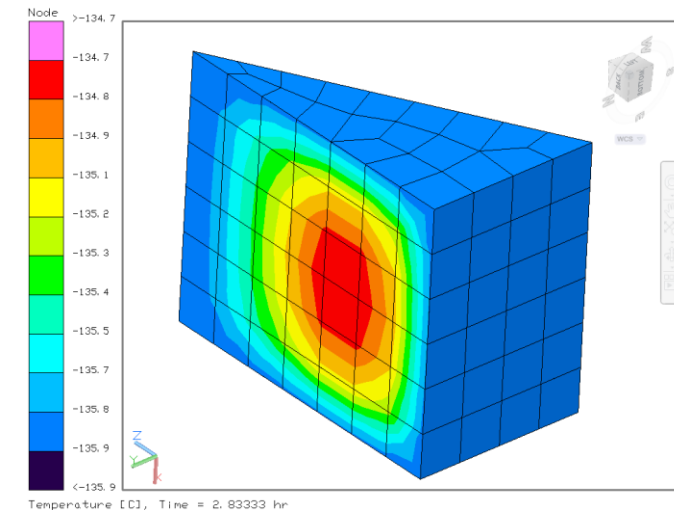
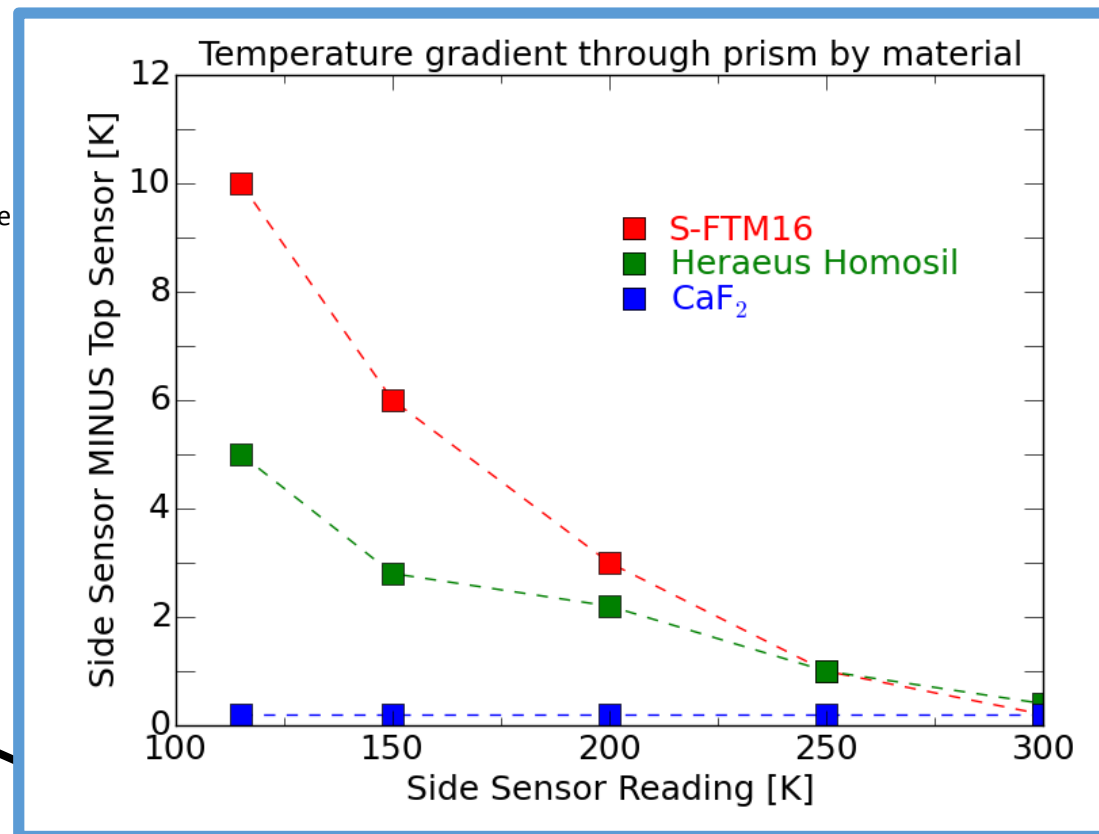
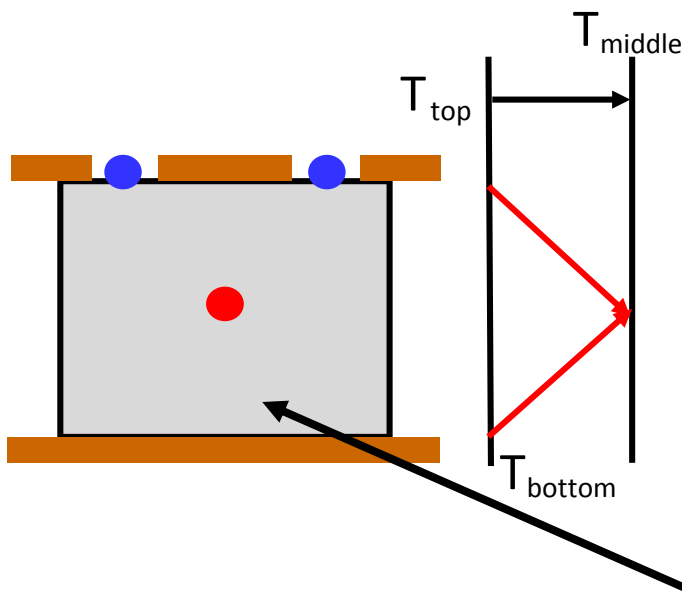


Eye level with prism



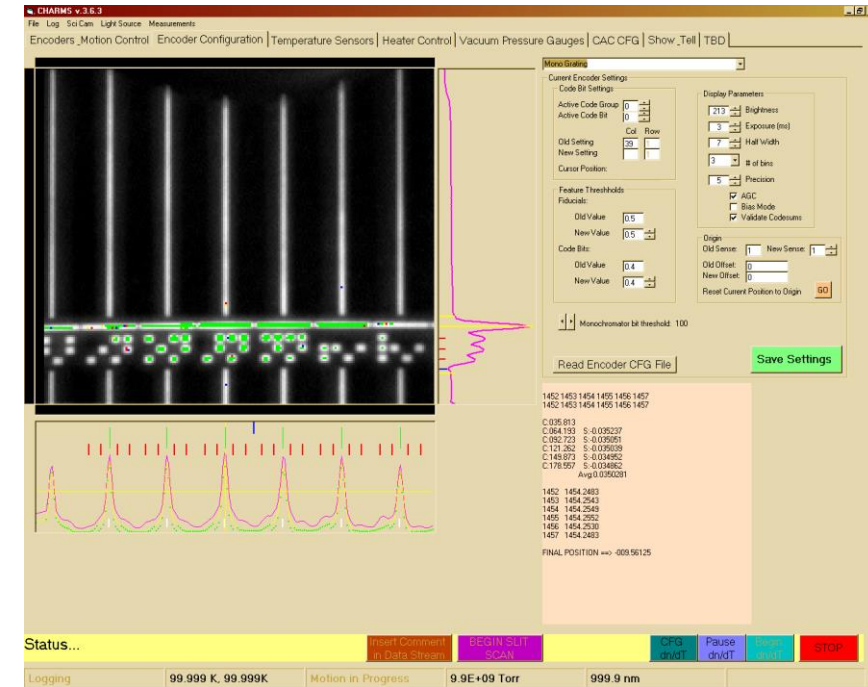
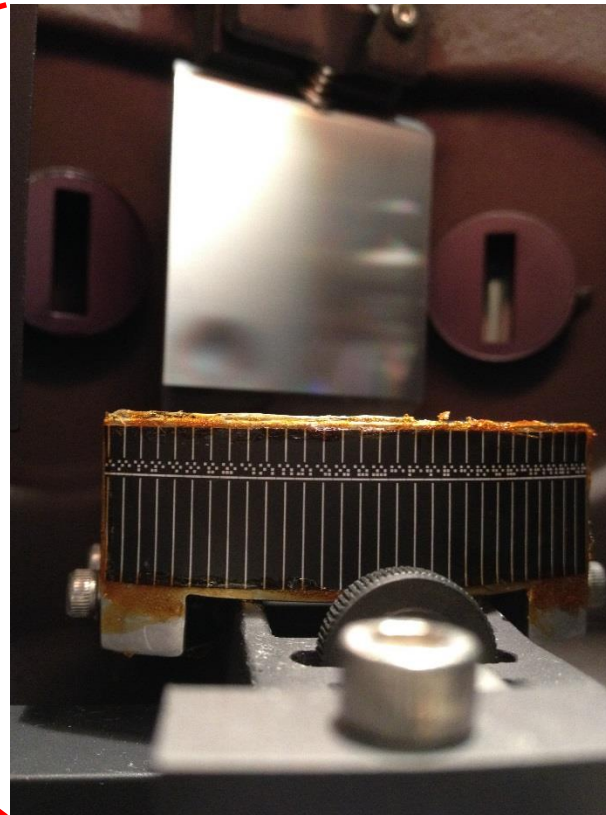
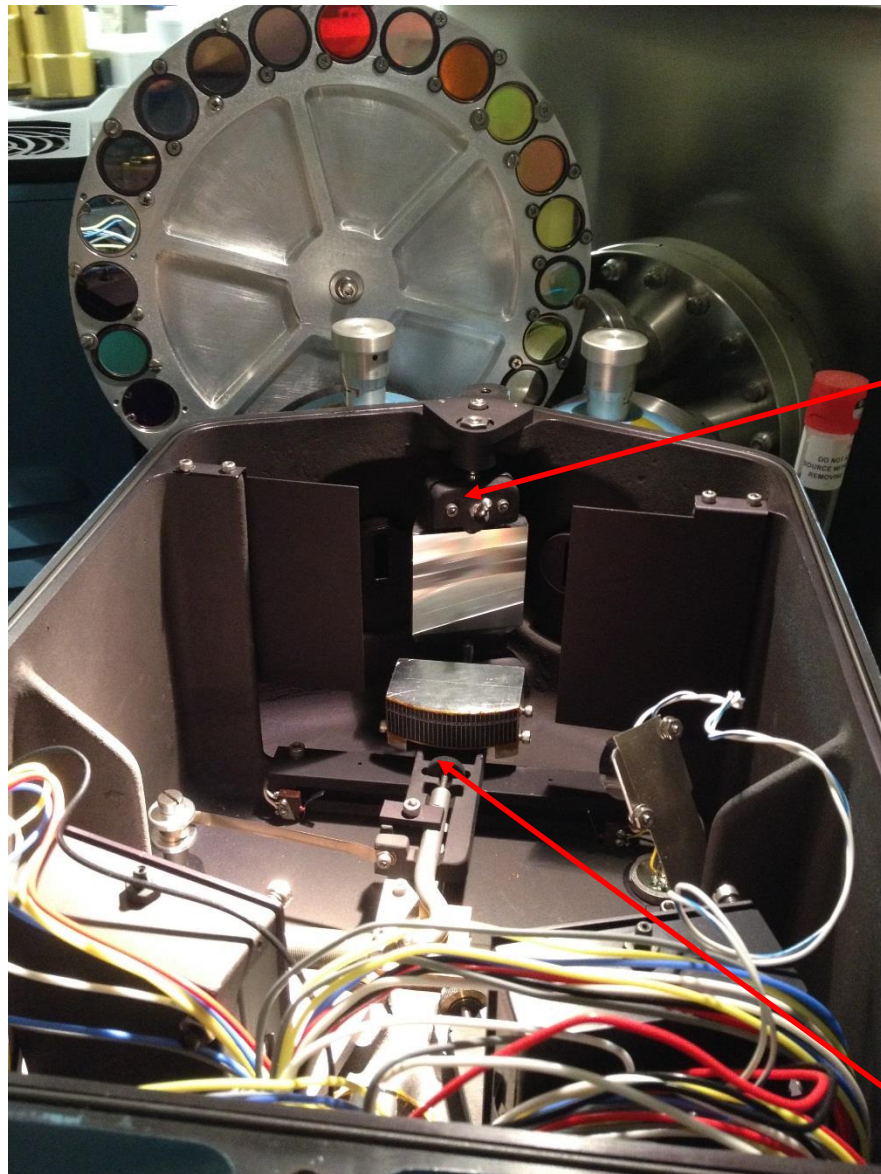
Sample Temperature, T

- sample sandwiched between two cryogen-cooled copper plates at essentially same T
- two T sensors on **top of prism**
- T_{sample} attributed to reading from sensor halfway up **side** of non-refracting face



Courtesy of S. Scola –
NASA LaRC

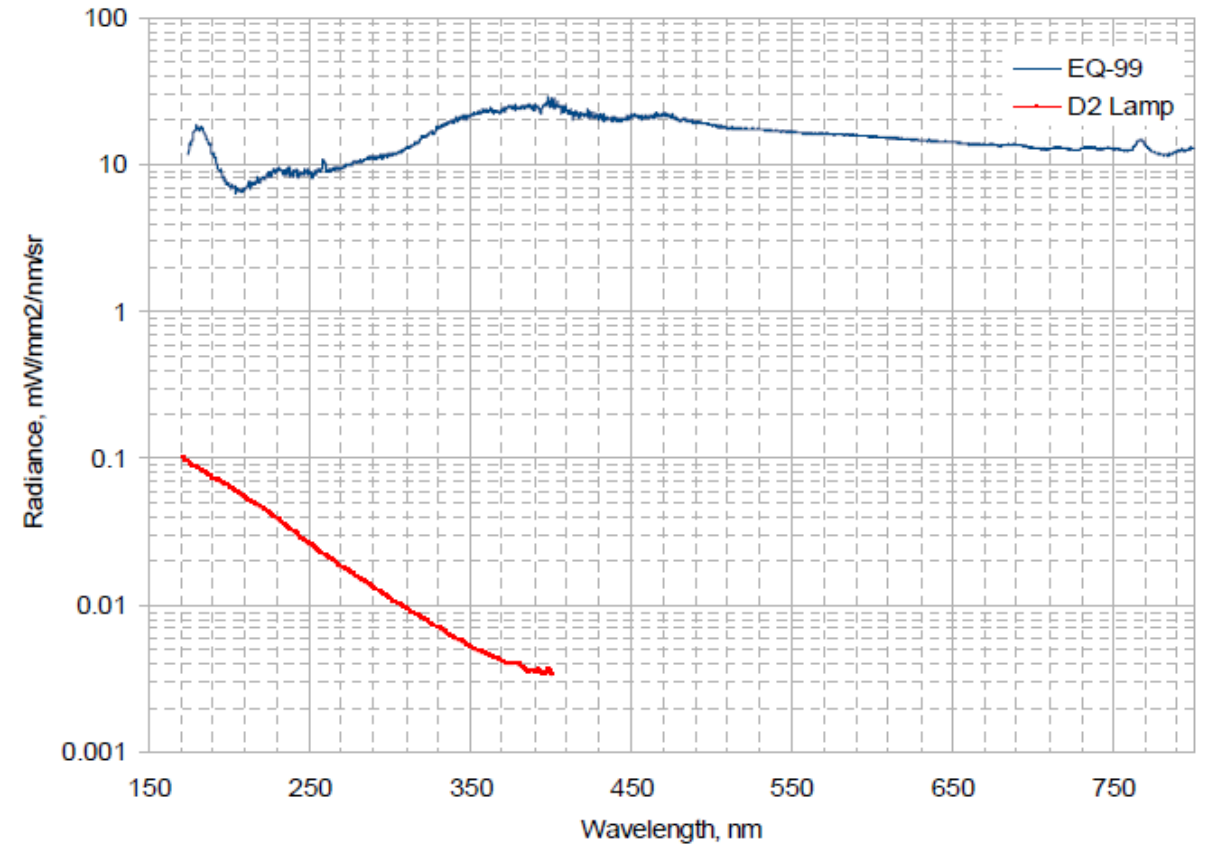
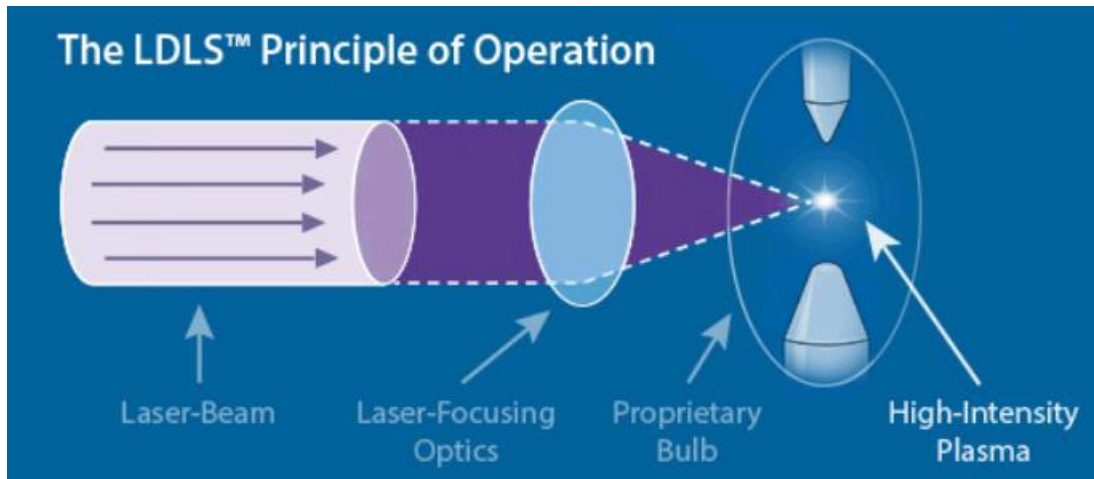
Wavelength Calibration & Encoder Technology



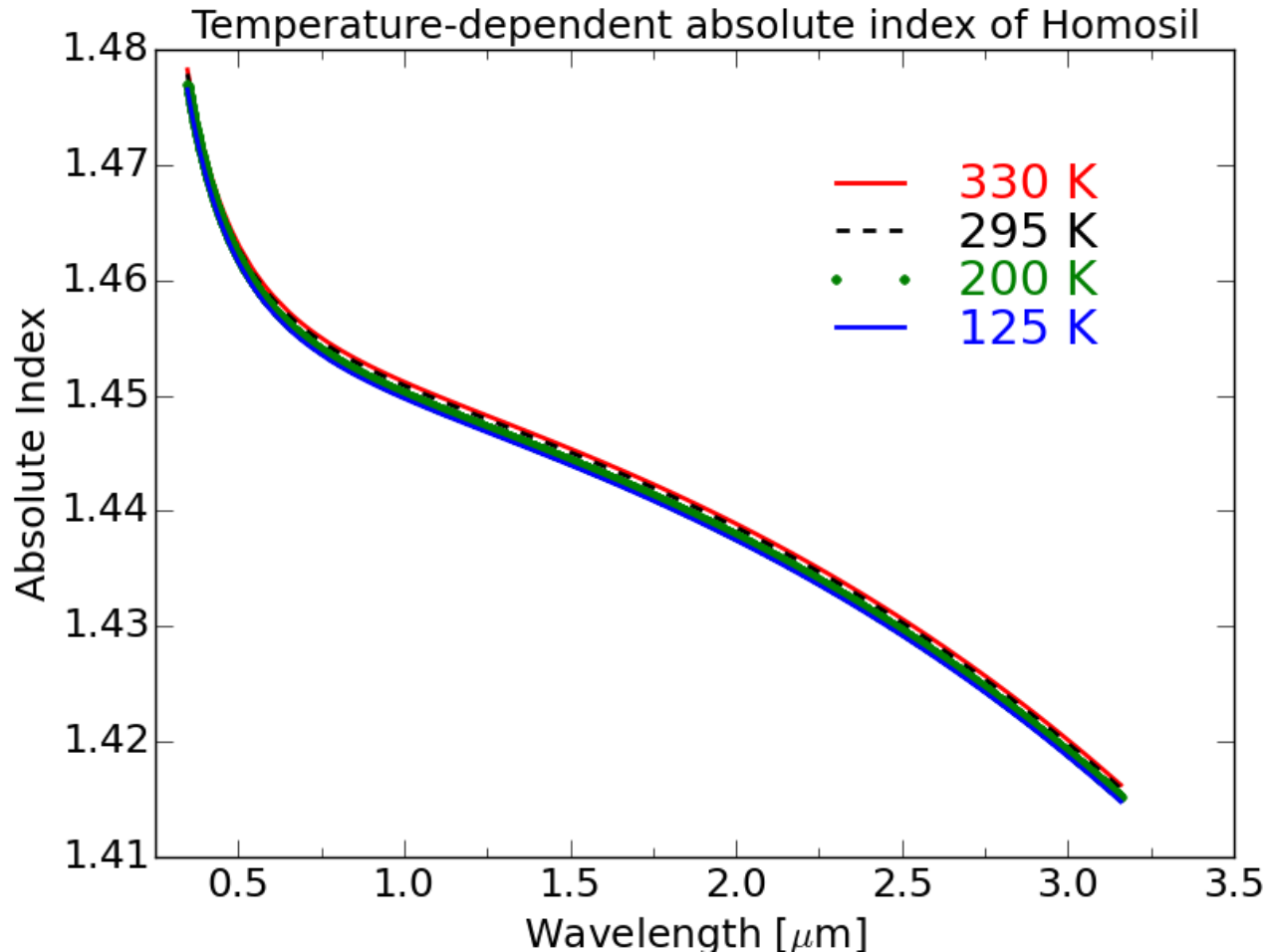
Laser Driven Plasma Light Source

Energetiq 99

- CW laser heats Xenon plasma
- Electrodeless
- 100 micron plasma size



CHARMS Measurements of Heraeus Homosil



Sellmeier Equation

$$n^2(\lambda, T) - 1 = \sum_{i=1}^3 \frac{S_i(T) \cdot \lambda^2}{\lambda^2 - \lambda_i^2(T)}$$

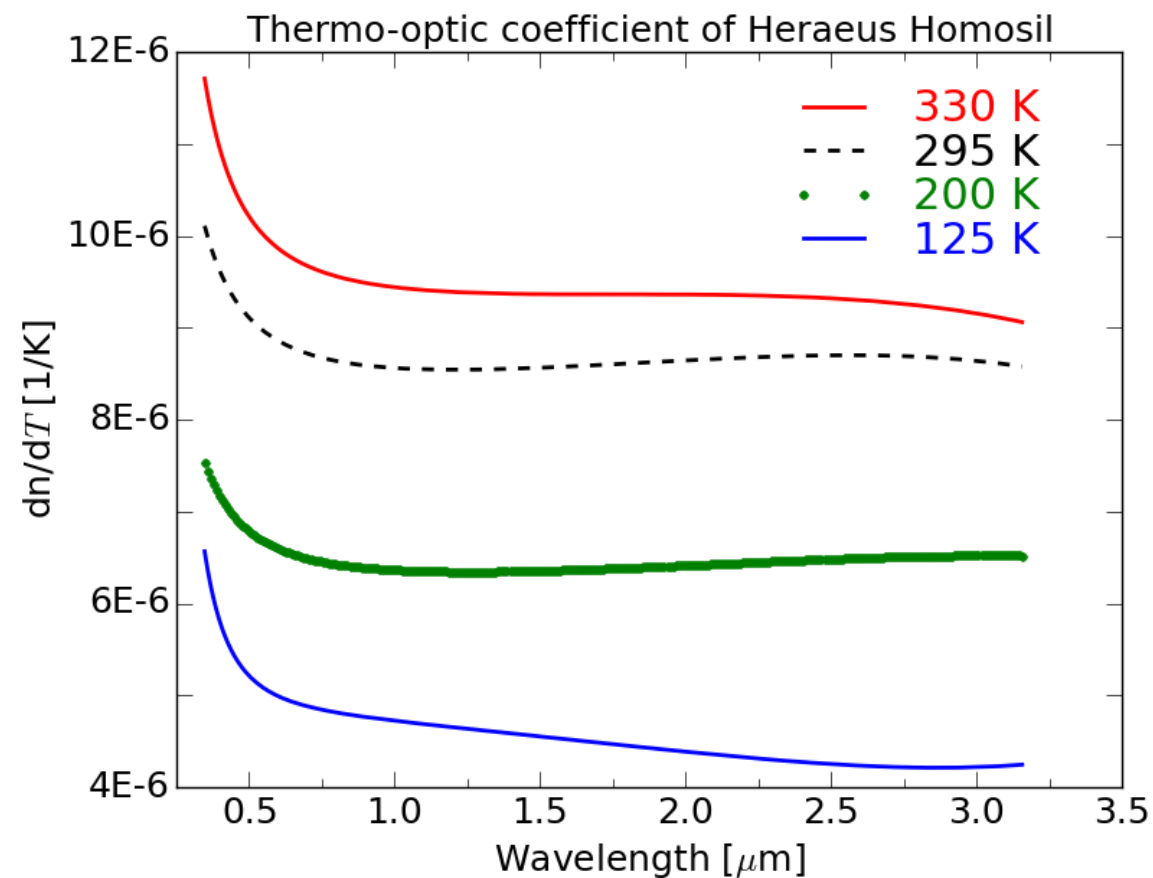
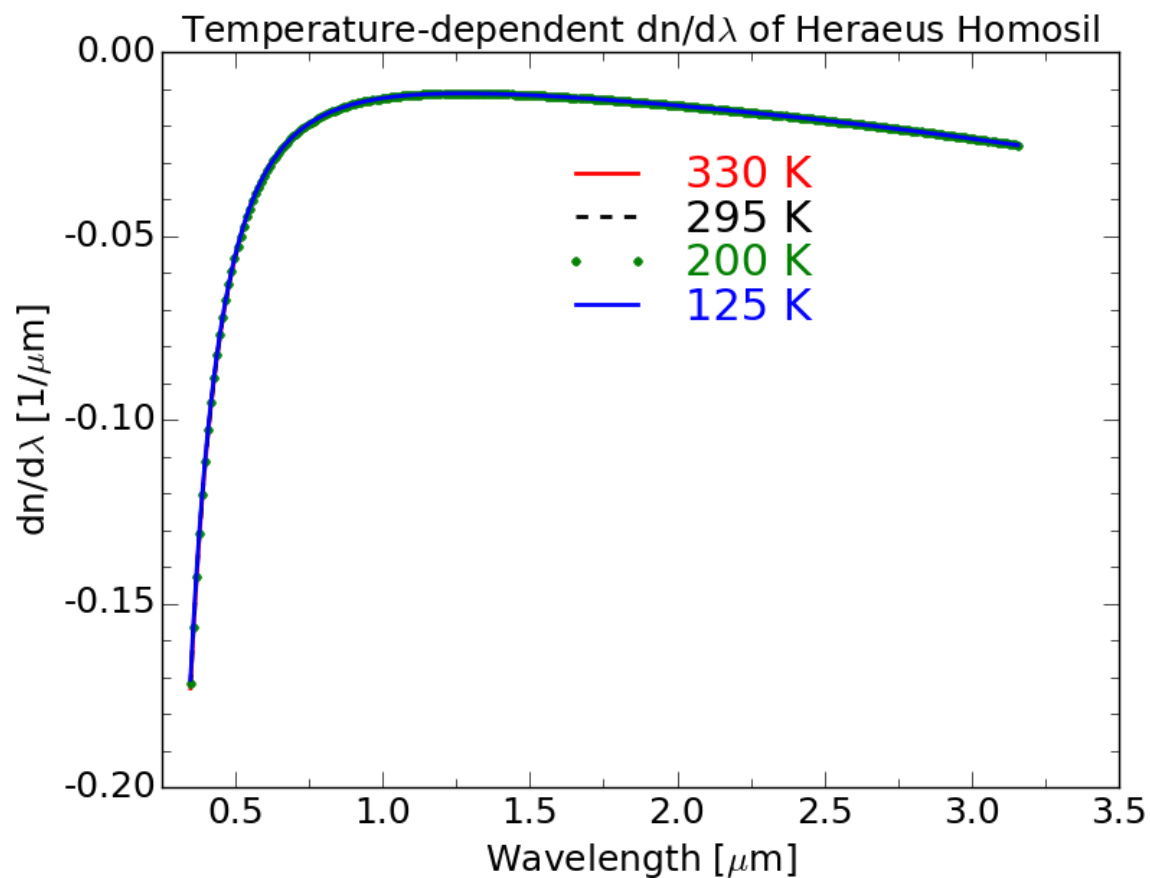
$$S_i(T) = \sum_{j=0}^3 S_{ij} \cdot T^j$$

$$\lambda_i(T) = \sum_{j=0}^3 \lambda_{ij} \cdot T^j$$

$$AAR = \frac{\sum_{k=1}^n |index_{measured} - index_{fit}|}{n}$$

$$\text{Homosil_AAR} = 5.07 \times 10^{-6}$$

Derived Properties of Heraeus Homosil



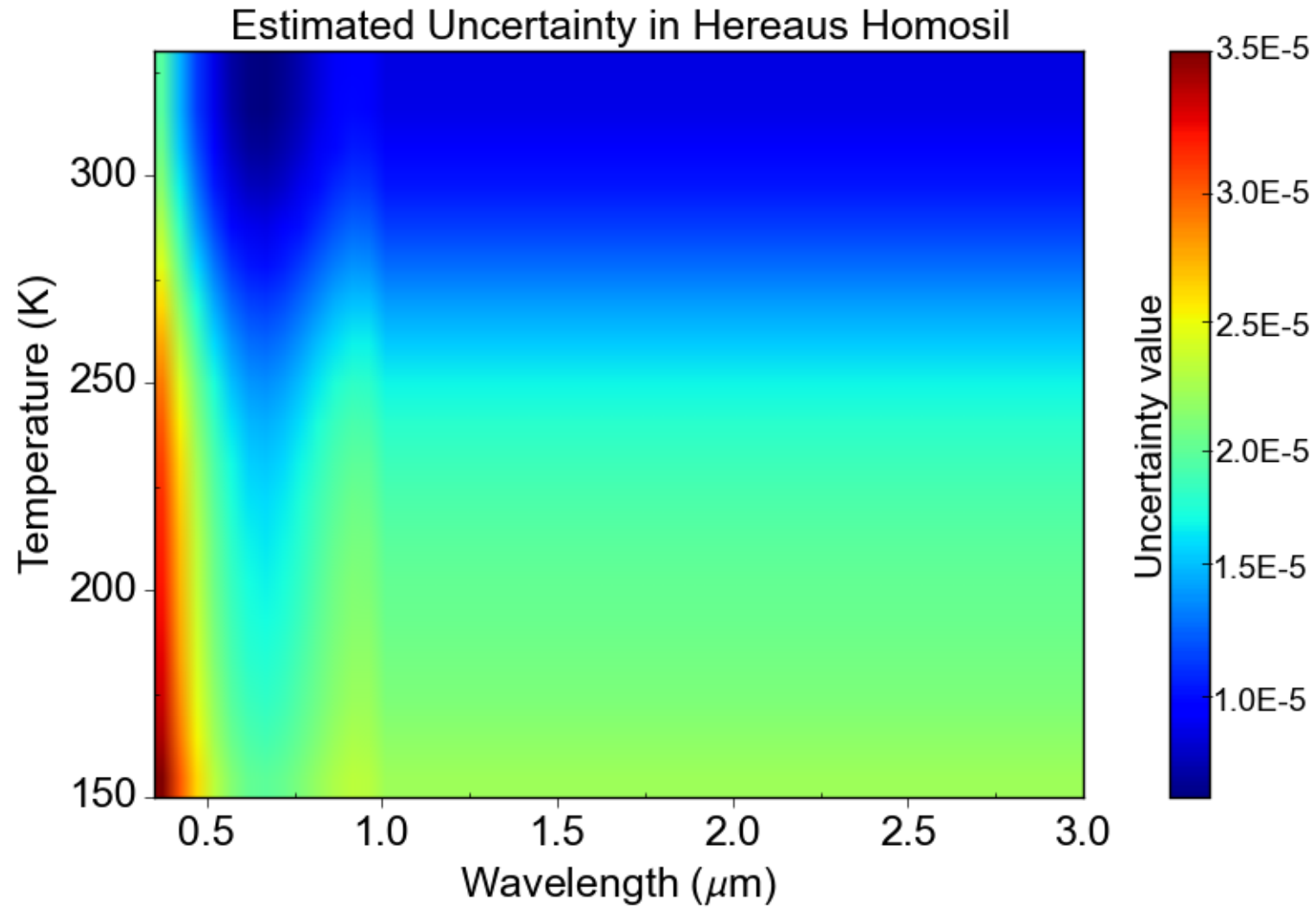
Example of Bookkeeping Error Budget

index n apex α deviation δ				$\frac{dn}{d\lambda}$ $\frac{dn}{dT}$ $\frac{dn}{d\alpha}$ $\frac{dn}{d\delta}$ $d\lambda$ dT da $d\delta$								\rightarrow	dn								
index n	apex a	alpha	delta d	SENSITIVITIES								FOR SPECIFIED PRISM				dn r.s.s.					
				$\frac{dn}{d\lambda}$	$\frac{dn}{dT}$	$\frac{dn}{d\alpha}$	$\frac{dn}{d\delta}$	$d\lambda$	dT	da	$d\delta$	$\frac{dn}{d\lambda}$	$\frac{dn}{dT}$	$\frac{dn}{d\alpha}$	$\frac{dn}{d\delta}$						
1.4574	10.0 deg	0.175 rads	4.595 deg	0.080 rads	0.00040/nm	0.000120/K	-2.64/rad	5.690/rad	0.10 nm	4.0E-05	0.1 K	1.2E-05	0.00014 deg	0.5 sec	#	-6.4E-06	0.00150 deg	5.4 sec	###	1.5E-04	1.7E-04
1.4574	20	0.349 rads	9.319 deg	0.163 rads	0.00040/nm	0.000120/K	-1.35/rad	2.786/rad	0.10 nm	4.0E-05	0.1 K	1.2E-05	0.00014 deg	0.5 sec	#	-3.3E-06	0.00150 deg	5.4 sec	###	7.3E-05	9.5E-05
1.4574	30	0.524 rads	14.321 deg	0.250 rads	0.00040/nm	0.000120/K	-0.93/rad	1.789/rad	0.10 nm	4.0E-05	0.1 K	1.2E-05	0.00014 deg	0.5 sec	#	-2.3E-06	0.00150 deg	5.4 sec	###	4.7E-05	7.4E-05
1.4574	40	0.698 rads	19.796 deg	0.346 rads	0.00040/nm	0.000120/K	-0.73/rad	1.267/rad	0.10 nm	4.0E-05	0.1 K	1.2E-05	0.00014 deg	0.5 sec	#	-1.8E-06	0.00150 deg	5.4 sec	###	3.3E-05	6.4E-05
1.4574	50	0.873 rads	26.038 deg	0.454 rads	0.00040/nm	0.000120/K	-0.63/rad	0.932/rad	0.10 nm	4.0E-05	0.1 K	1.2E-05	0.00014 deg	0.5 sec	#	-1.5E-06	0.00150 deg	5.4 sec	###	2.4E-05	5.9E-05
1.4574	58	1.012 rads	31.912 deg	0.557 rads	0.00040/nm	0.000120/K	-0.58/rad	0.730/rad	0.10 nm	4.0E-05	0.1 K	1.2E-05	0.00014 deg	0.5 sec	#	-1.4E-06	0.00150 deg	5.4 sec	###	1.9E-05	5.6E-05
2.6	10	0.175 rads	16.195 deg	0.283 rads	0.00040/nm	0.000120/K	-9.27/rad	5.588/rad	0.10 nm	4.0E-05	0.1 K	1.2E-05	0.00014 deg	0.5 sec	#	-2.3E-05	0.00150 deg	5.4 sec	###	1.5E-04	1.7E-04
2.6	15	0.262 rads	24.677 deg	0.431 rads	0.00040/nm	0.000120/K	-6.27/rad	3.603/rad	0.10 nm	4.0E-05	0.1 K	1.2E-05	0.00014 deg	0.5 sec	#	-1.5E-05	0.00150 deg	5.4 sec	###	9.4E-05	1.2E-04
2.6	20	0.349 rads	33.678 deg	0.588 rads	0.00040/nm	0.000120/K	-4.80/rad	2.569/rad	0.10 nm	4.0E-05	0.1 K	1.2E-05	0.00014 deg	0.5 sec	#	-1.2E-05	0.00150 deg	5.4 sec	###	6.7E-05	9.1E-05
2.6	25	0.436 rads	43.491 deg	0.759 rads	0.00040/nm	0.000120/K	-3.95/rad	1.910/rad	0.10 nm	4.0E-05	0.1 K	1.2E-05	0.00014 deg	0.5 sec	#	-9.7E-06	0.00150 deg	5.4 sec	###	5.0E-05	7.7E-05
2.6	30	0.524 rads	54.587 deg	0.953 rads	0.00040/nm	0.000120/K	-3.42/rad	1.429/rad	0.10 nm	4.0E-05	0.1 K	1.2E-05	0.00014 deg	0.5 sec	#	-8.4E-06	0.00150 deg	5.4 sec	###	3.7E-05	6.7E-05
3.4	10	0.175 rads	24.475 deg	0.427 rads	0.00040/nm	0.000120/K	-13.95/rad	5.479/rad	0.10 nm	4.0E-05	0.1 K	1.2E-05	0.00014 deg	0.5 sec	#	-3.4E-05	0.00150 deg	5.4 sec	###	1.4E-04	1.6E-04
3.4	14	0.244 rads	34.958 deg	0.610 rads	0.00040/nm	0.000120/K	-10.11/rad	3.734/rad	0.10 nm	4.0E-05	0.1 K	1.2E-05	0.00014 deg	0.5 sec	#	-2.5E-05	0.00150 deg	5.4 sec	###	9.8E-05	1.2E-04
3.4	18	0.314 rads	46.265 deg	0.807 rads	0.00040/nm	0.000120/K	-8.03/rad	2.707/rad	0.10 nm	4.0E-05	0.1 K	1.2E-05	0.00014 deg	0.5 sec	#	-2.0E-05	0.00150 deg	5.4 sec	###	7.1E-05	9.6E-05
3.4	22	0.384 rads	58.895 deg	1.028 rads	0.00040/nm	0.000120/K	-6.75/rad	1.994/rad	0.10 nm	4.0E-05	0.1 K	1.2E-05	0.00014 deg	0.5 sec	#	-1.6E-05	0.00150 deg	5.4 sec	###	5.2E-05	8.0E-05
4.0	10	0.175 rads	30.806 deg	0.538 rads	0.00040/nm	0.000120/K	-17.48/rad	5.377/rad	0.10 nm	4.0E-05	0.1 K	1.2E-05	0.00014 deg	0.5 sec	#	-4.3E-05	0.00150 deg	5.4 sec	###	1.4E-04	1.6E-04
4.0	12.5	0.218 rads	39.130 deg	0.683 rads	0.00040/nm	0.000120/K	-14.13/rad	4.134/rad	0.10 nm	4.0E-05	0.1 K	1.2E-05	0.00014 deg	0.5 sec	#	-3.5E-05	0.00150 deg	5.4 sec	###	1.1E-04	1.3E-04
4.0	15	0.262 rads	47.947 deg	0.837 rads	0.00040/nm	0.000120/K	-11.92/rad	3.267/rad	0.10 nm	4.0E-05	0.1 K	1.2E-05	0.00014 deg	0.5 sec	#	-2.9E-05	0.00150 deg	5.4 sec	###	8.6E-05	1.1E-04
4.0	17.5	0.305 rads	57.461 deg	1.003 rads	0.00040/nm	0.000120/K	-10.39/rad	2.608/rad	0.10 nm	4.0E-05	0.1 K	1.2E-05	0.00014 deg	0.5 sec	#	-2.5E-05	0.00150 deg	5.4 sec	###	6.8E-05	9.5E-05

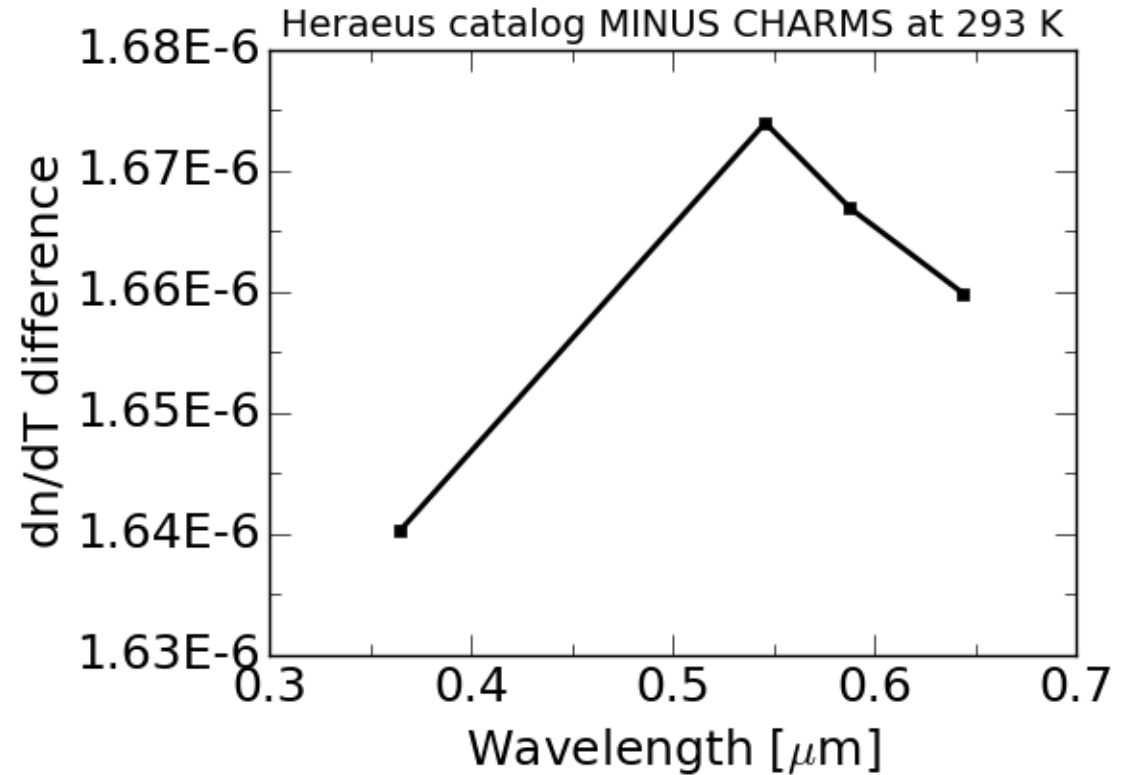
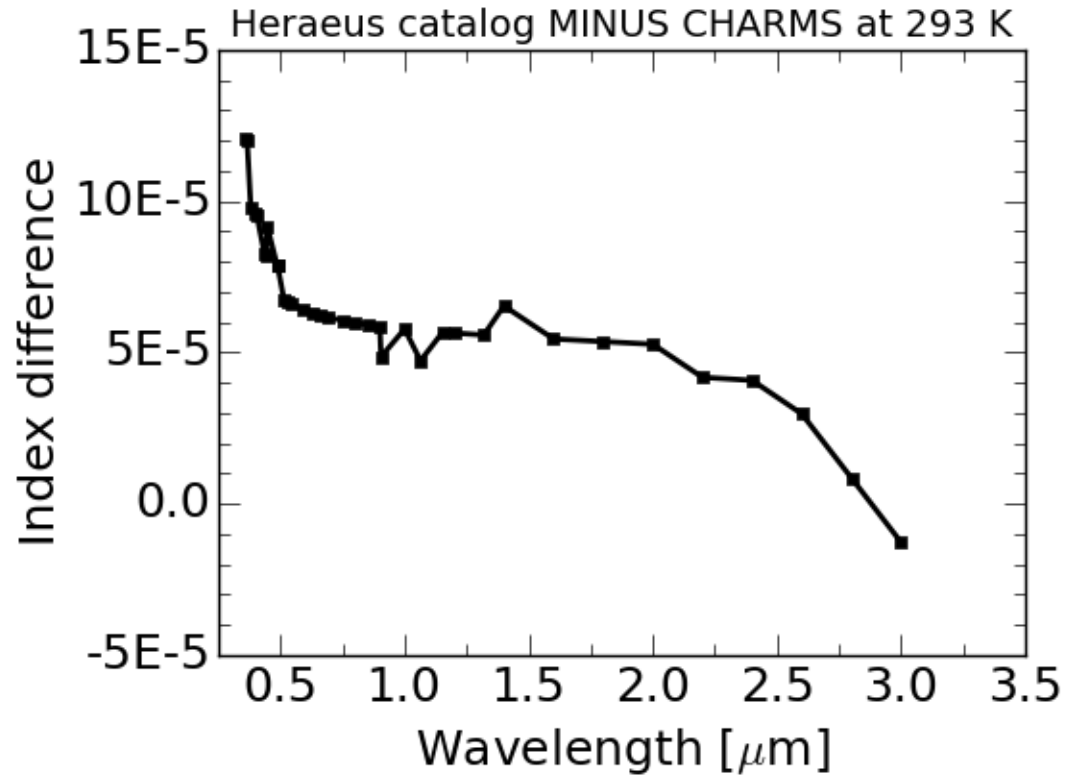
- uncertainty governed by all eight quantities in the red box for each measurement for a given specimen (green box)

so, a refractometer should not list a single number for accuracy

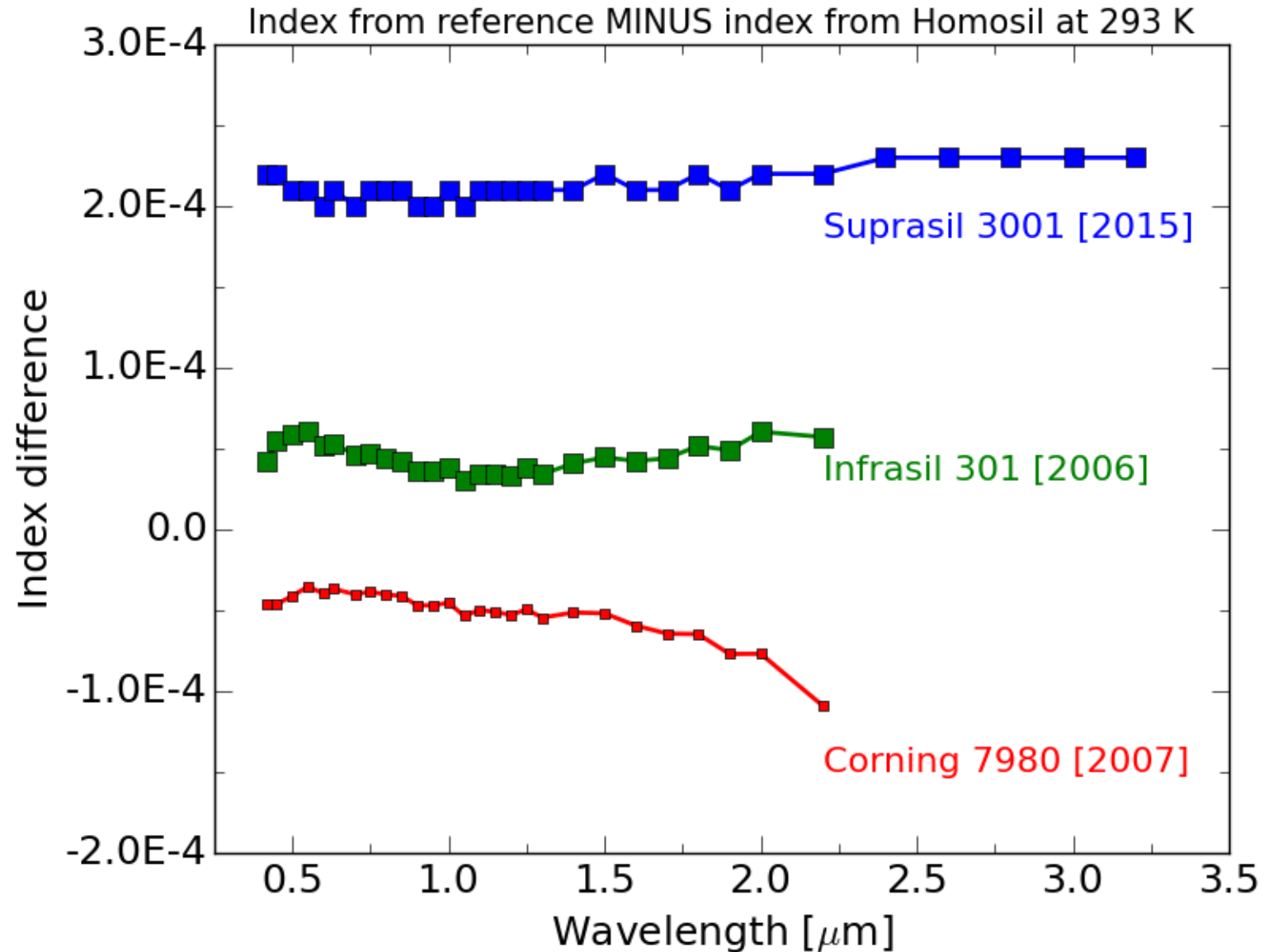
Measurement Uncertainties



Comparison of Heraeus Catalog with CHARMS



Comparison with other fused silica-based glasses



Backup

